

<b>Notic of References Cited</b>			Application No. <b>45787</b>		Applicant(s) <b>Saitoh et al</b>	
			Examiner <b>B. Lee</b>		Group Art Unit <b>2817</b>	
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<b>U.S. PATENT DOCUMENTS</b>						
*	DOCUMENT NO.	DATE	NAME		CLASS	SUBCLASS
A	<b>U52002/6175784A</b>	<b>11/2002</b>	<b>Yamashita et al</b>		<b>333</b>	<b>239</b>
B	<b>5982256</b>	<b>11/1999</b>	<b>Uchimura et al</b>		<b>333</b>	<b>248X</b>
C	<b>5861782</b>	<b>1/1999</b>	<b>Saitoh</b>		<b>333</b>	<b>248</b>
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<b>FOREIGN PATENT DOCUMENTS</b>						
*	DOCUMENT NO.	DATE	COUNTRY	NAME	CLASS	SUBCLASS
N						
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<b>NON-PATENT DOCUMENTS</b>						
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(See Manual of Patent Examining Procedure, Section 707.05(a).)